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| APPLICATION NO. | FILING DATE | FIRST NAMED INVENTOR | ATTORNEY DOCKET NO. | CONFIRMATION NO. |
|--|-------------------------|----------------------|---------------------|------------------|
| 10/820,525 | 04/07/2004 | Qingguo Wu | NOVLP091/002889 | 8337 |
| 22434 7. | 590 09/07/2006 | | EXAMINER | |
| BEYER WEA | VER & THOMAS, LL | MALDONADO, JULIO J | | |
| P.O. BOX 70250 OAKLAND, CA 94612-0250 | | | ART UNIT | PAPER NUMBER |
| Ornicality, C | 311 91012 0230 | | 2823 | |
| | DATE MAILED: 09/07/2006 | | | 6 |

Please find below and/or attached an Office communication concerning this application or proceeding.

| | | Application No. | Applicant(s) | | | | |
|--|--|---|--------------------------|--|--|--|--|
| | | 10/820,525 | WU ET AL. | | | | |
| | Office Action Summary | Examiner | Art Unit | | | | |
| | | Julio J. Maldonado | 2823 | | | | |
| Period fo | The MAILING DATE of this communication app or Reply | ears on the cover sheet with the c | orrespondence address | | | | |
| A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication. - If NO pend for reply is specified above, the maximum statutory pend will apply and will expire SIX (6) MONTHS from the mailing date of this communication. - Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b). | | | | | | | |
| Status | | | | | | | |
| 1) | Responsive to communication(s) filed on | | | | | | |
| | | action is non-final. | | | | | |
| 3)□ | ,— | | | | | | |
| | closed in accordance with the practice under Ex parte Quayle, 1935 C.D. 11, 453 O.G. 213. | | | | | | |
| Dispositi | on of Claims | | | | | | |
| 4)⊠ | Claim(s) 1-31 is/are pending in the application. | | | | | | |
| | 4a) Of the above claim(s) is/are withdrawn from consideration. | | | | | | |
| 5)□ |)☐ Claim(s) is/are allowed. | | | | | | |
| 6)⊠ | Claim(s) <u>1-31</u> is/are rejected. | | | | | | |
| 7) | Claim(s) is/are objected to. | | | | | | |
| 8)[| Claim(s) are subject to restriction and/or | election requirement. | | | | | |
| Applicati | on Papers | | | | | | |
| 9)[| The specification is objected to by the Examiner | r. | | | | | |
| 10) 🗌 | The drawing(s) filed on is/are: a)☐ acce | epted or b) objected to by the E | Examiner. | | | | |
| | Applicant may not request that any objection to the o | drawing(s) be held in abeyance. See | 37 CFR 1.85(a). | | | | |
| Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d). | | | | | | | |
| 11) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152. | | | | | | | |
| Priority u | inder 35 U.S.C. § 119 | | | | | | |
| _ | 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some * c) None of: | | | | | | |
| | 1. Certified copies of the priority documents have been received. | | | | | | |
| | 2. Certified copies of the priority documents have been received in Application No | | | | | | |
| | 3. Copies of the certified copies of the prior | | d in this National Stage | | | | |
| • • | application from the International Bureau (PCT Rule 17.2(a)). | | | | | | |
| * See the attached detailed Office action for a list of the certified copies not received. | | | | | | | |
| | | · | | | | | |
| Attachm ent | (s) | | | | | | |
| 1) Notice of References Cited (PTO-892) 4) Interview Summary (PTO-413) | | | | | | | |
| | e of Draftsperson's Patent Drawing Review (PTO-948) nation Disclosure Statement(s) (PTO/SB/08) | Paper No(s)/Mail Da 5) Notice of Informal Pa | | | | | |
| Paper No(s)/Mail Date <u>See Continuation Sheet.</u> 6) Other: | | | | | | | |

Continuation of Attachment(s) 3). Information Disclosure Statement(s) (PTO/SB/08), Paper No(s)/Mail Date :20060725 20060424 20060227 20051219 20051019 20050824 20050627 20040716.

DETAILED ACTION

Claim Rejections - 35 USC § 103

- 1. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 2. Claims 1-16 and 18-31 are rejected under 35 U.S.C. 103(a) as being unpatentable over Fukazawa et al. (U.S. 2006/0110931 A1, hereinafter Fukazawa) in view of the following comments.

Fukazawa (Fig.1) teaches forming a low-k dielectric layer for multilayered wirings, including the steps of providing a substrate (4) to a deposition chamber (1); providing an unsaturated carbon doped oxide precursor to the deposition chamber (1); igniting and maintaining a plasma in the deposition chamber (1) using radio frequency power having high frequency and low frequency components, wherein at least about 1% to 50% of total radiofrequency is provided by the low frequency component, which has a frequency of 2MHz or less, the high frequency component has a frequency selected from the consisting of 13.56 MHz, 27 MHZ and 60 MHz, wherein the temperature of between 49°C to 550°C, and the pressure is between 1-10 Torr; depositing the low-k dielectric layer under said conditions, wherein said low-k dielectric layer has a dielectric constant of less than 3.5, and wherein the deposition chamber further comprises a showerhead that serves as one plate of a plasma producing capacitor and a grounded block that serves as a second plate of the plasma producing capacitor and can have a

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separation of, for example 24 mm (Fukazawa, [0034] – [0055] and [0068] – [0087]). Furthermore, Fukazawa teaches wherein the carbon doped oxide precursor can be 1, 3-divinyltetramethyldisiloxane (Fukazawa, [0045] – [0046]).

Fukazawa fails to disclose wherein at least 2 percent of total radio frequency power is provided by the low frequency component, which has a frequency of between about 100kHZ and 600kHz, wherein the high frequency component has a frequency between 2 MHz and 60MHz, wherein the temperature is between 300 and 425°C, wherein the pressure is between 2 and 20 Torr, wherein the dielectric constant is not greater than about 3 and wherein the separation gap between the showerhead and the block is maintained at a distance of between about 5 mm and 100 mm. However, in the case where the claimed ranges "overlap or lie inside ranges disclosed by the prior art" a prima facie case of obviousness exists. MPEP 2144.05. Therefore, it would have been obvious to one of ordinary skill in the art at the time the invention was made to use the frequency, separation gap, temperature and pressure to obtain the dielectric layer having the dielectric constant disclosed in Fukazawa to arrive at the claimed invention.

Still, Fukazawa fails to teach wherein the low frequency component of the radio frequency power has a power of between about 0.02 and 20 Watts/cm² of the substrate surface area, and pulsing the high frequency component at a frequency of between about 500 Hz and 10 kHz during deposition having a duty cycle of between 20 and 80%. However, the selection of the recited power and frequency is obvious because it is a matter of determining optimum process condition by routine experimentation with a limited number of species to obtain desired plasma conditions. Therefore, it would have

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been obvious to one of ordinary skill in the art at the time the invention was made to arrive at the recited specification through routine experimentation.

Fukazawa fails to disclose wherein the carbon doped dielectric layer has a residual tensile or compressive stress of magnitude less than about 50 MPa. However, the same material would be treated in the same manner and therefore the recited results would be obtained.

3. Claim 17 is rejected under 35 U.S.C. 103(a) as being unpatentable over Fukazawa ('931) as applied to claims 1-16 and 18-31 above, and further in view of Rhee et al. (U.S. 7,087,271 A1, hereinafter Rhee).

Fukazawa substantially teaches all aspects of the invention including wherein the carbon doped oxide precursor has the general formula $Si_{\alpha}O_{\alpha-1}R_{2\alpha-\beta+2}(OR')_{\beta}$, wherein α is an integer of 1-3, β can be 0 and R is C_{1-6} hydrocarbon attached to Si and R' is C_{1-6} unattached to Si (Fukazawa, [0045] – [0046]). Fukazawa fails to teach wherein the carbon doped oxide precursor is ethynyltrimethylsilane. However, Rhee teaches a related method to form low dielectric constant layers teaches providing a substrate in a CVD chamber; introducing carbon doped oxide precursor into the chamber; and depositing said low-k dielectric layer, wherein said carbon doped oxide precursor is selected from a group including ethynyltrimethylsilane (Rhee, column 3, lines 38-52). It would have been within the scope of one of ordinary skill in the art to combine the teachings of Fukazawa and Rhee to enable depositing the low-k dielectric layer of Fukazawa using the precursor according to the teachings of Rhee because one of ordinary skill in the art at the time the invention was made would have been motivated

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to look to alternative suitable methods of forming the disclosed low-k dielectric layer of

Fukazawa and art recognized suitability for an intended purpose has been recognized

to be motivation to combine (MPEP 2144.07), and furthermore, because this would

result in dielectric layer with dielectric constant of less than 2.6 (Rhee, column 1, lines

56 - 60).

Conclusion

4. Applicants are encouraged, where appropriate, to check Patent Application

Information Retrieval (PAIR) (http://portal.uspto.gov/external/portal/pair) which provides

applicants direct secure access to their own patent application status information, as

well as to general patent information publicly available.

5. Any inquiry concerning this communication or earlier communications from the

examiner should be directed to examiner Julio J. Maldonado whose telephone number

is (571) 272-1864. The examiner can normally be reached on Monday through Friday.

6. If attempts to reach the examiner by telephone are unsuccessful, the examiner's

supervisor, Matthew Smith, can be reached on (571) 272-1907. The fax number for this

group is 571-273-8300. Updates can be found at

http://www.uspto.gov/web/info/2800.htm.

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